

Title (en)

METHOD FOR THE SELECTIVE ANALYSIS OF TRACES OF INDIVIDUAL COMPONENTS IN GASES AND LIQUIDS

Publication

EP 0068443 B1 19860917 (DE)

Application

EP 82105550 A 19820624

Priority

DE 3125335 A 19810627

Abstract (en)

[origin: US4468468A] The analysis comprises first enriching the component to be determined (target component) by contacting an non porous solid surface with the gas or the liquid to be investigated and depositing the target component from the gaseous or liquid phase onto the solid surface in the range of a monolayer preferably within the first monolayer. The deposition is effected by absorbing the target component either directly or in the form of a derivative product, which can then be detected by introducing the solid surface with the enriched target component into a mass spectrometer. Surface sensitive mass analyzers, such as secondary ion mass spectrometers or laser activated mass analyzers, have been proven successful.

IPC 1-7

H01J 49/10; **H01J 49/14**; **H01J 49/16**

IPC 8 full level

G01N 1/22 (2006.01); **G01N 23/225** (2006.01); **G01N 27/62** (2006.01); **G01N 33/52** (2006.01); **H01J 49/10** (2006.01); **H01J 49/14** (2006.01); **H01J 49/16** (2006.01); **H01J 49/26** (2006.01)

CPC (source: EP US)

H01J 49/164 (2013.01 - EP US); **Y10T 436/24** (2015.01 - EP US); **Y10T 436/255** (2015.01 - EP US)

Cited by

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Designated contracting state (EPC)

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EP 0068443 A2 19830105; **EP 0068443 A3 19840704**; **EP 0068443 B1 19860917**; AT E22368 T1 19861015; CA 1195013 A 19851008; DE 3125335 A1 19830113; DE 3273325 D1 19861023; JP S589040 A 19830119; US 4468468 A 19840828; US 4527059 A 19850702

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